

IRFR220

N-channel enhancement mode field effect transistor

Rev. 01 — 14 August 2001

Product data

1. Description

N-channel enhancement mode field-effect transistor in a plastic package using **TrenchMOS™¹** technology.

Product availability:

IRFR220 in SOT428 (D-PAK).

2. Features

- Fast switching
- Low on-state resistance
- Surface mount package.

3. Applications

- Switched mode power supplies
- DC to DC converters.

4. Pinning information

Table 1: Pinning - SOT428 (D-PAK), simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1	gate (g)		
2	drain (d) [1]		
3	source (s)		
mb	mounting base; connected to drain (d)		

SOT428 (D-PAK)

[1] It is not possible to make connection to pin 2 of the SOT428 package.

1. TrenchMOS is a trademark of Koninklijke Philips Electronics N.V.



5. Quick reference data

Table 2: Quick reference data

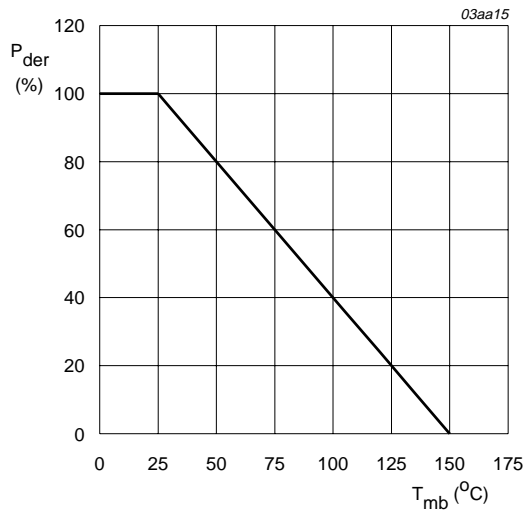
Symbol	Parameter	Conditions	Typ	Max	Unit
V_{DS}	drain-source voltage (DC)	$T_j = 25$ to 150 °C	–	200	V
I_D	drain current (DC)	$T_{mb} = 25$ °C; $V_{GS} = 10$ V	–	4.8	A
P_{tot}	total power dissipation	$T_{mb} = 25$ °C	–	42	W
T_j	junction temperature		–	150	°C
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10$ V; $I_D = 2.9$ A	0.7	0.8	Ω

6. Limiting values

Table 3: Limiting values

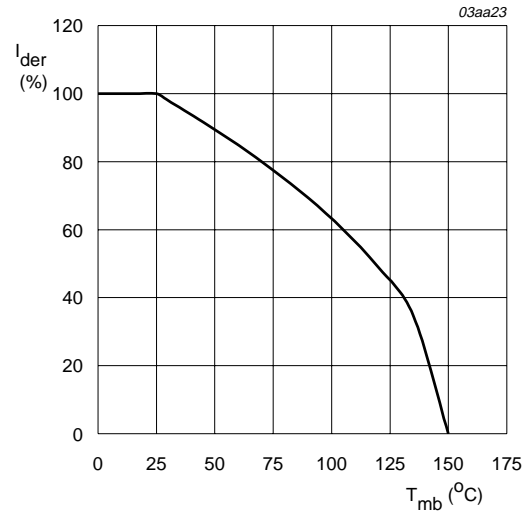
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage (DC)	$T_j = 25$ to 150 °C	–	200	V
V_{DGR}	drain-gate voltage (DC)	$T_j = 25$ to 150 °C; $R_{GS} = 20$ k Ω	–	200	V
V_{GS}	gate-source voltage (DC)		–	± 20	V
I_D	drain current (DC)	$T_{mb} = 25$ °C; $V_{GS} = 10$ V; Figure 2 and 3	–	4.8	A
		$T_{mb} = 100$ °C; $V_{GS} = 10$ V; Figure 2 and 3	–	3.0	A
I_{DM}	peak drain current	$T_{mb} = 25$ °C; $t_p \leq 10$ μ s	–	19	A
P_{tot}	total power dissipation	$T_{mb} = 25$ °C; Figure 1	–	42	W
T_{stg}	storage temperature		–55	+150	°C
T_j	operating junction temperature		–55	+150	°C
Source-drain (reverse) diode					
I_S	source (diode forward) current (DC)	$T_{mb} = 25$ °C	–	4.8	A
I_{SM}	peak (diode forward) source current	$T_{mb} = 25$ °C; $t_p \leq 10$ μ s	–	19	A



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

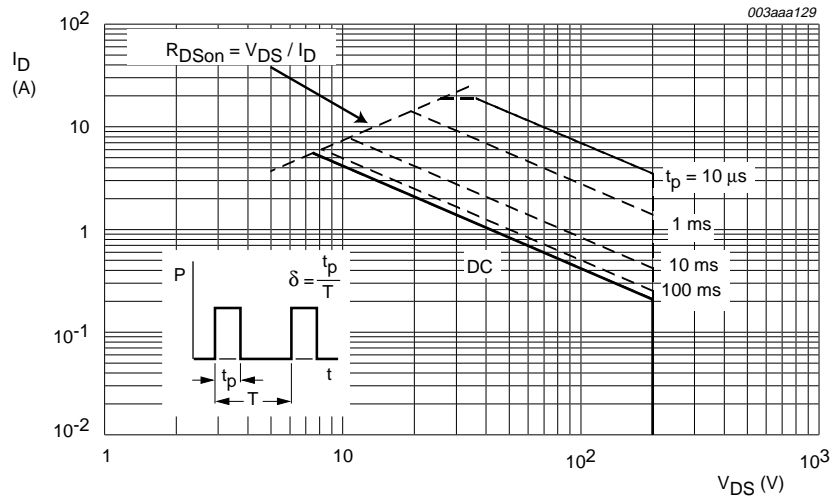
Fig 1. Normalized total power dissipation as a function of mounting base temperature.



V_{GS} ≥ 10 V

$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature.



T_{mb} = 25 °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Value	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	mounted on a metal clad substrate; Figure 4	3	K/W

7.1 Transient thermal impedance

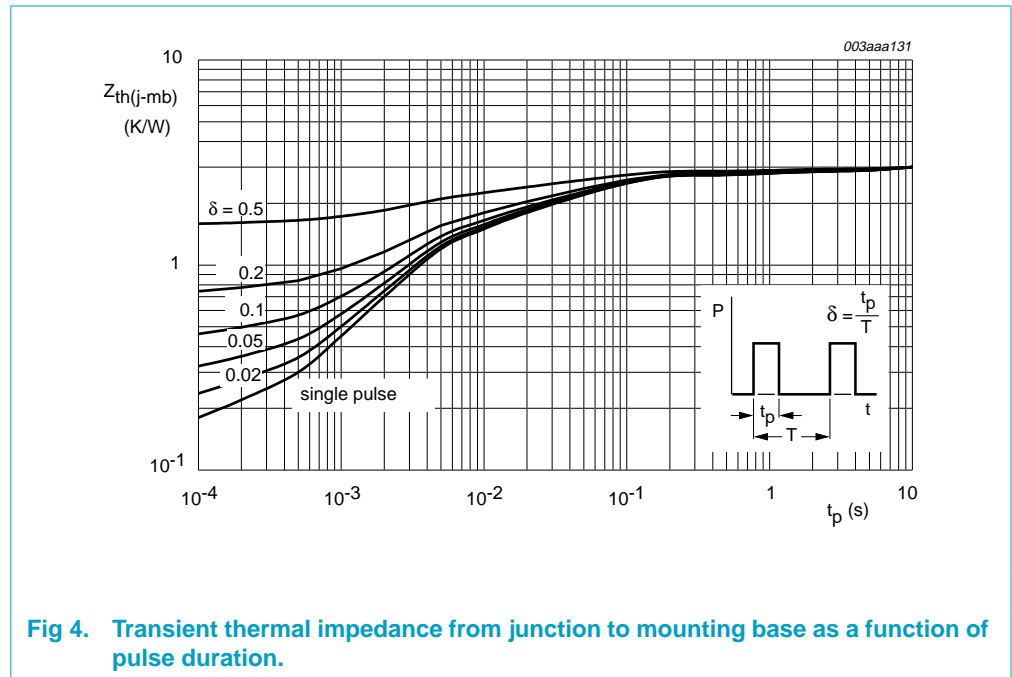


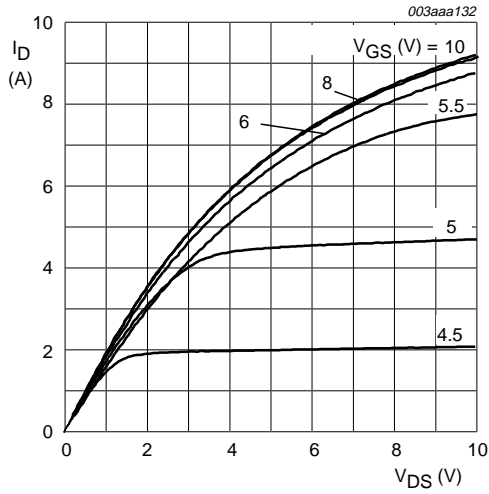
Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration.

8. Characteristics

Table 5: Characteristics

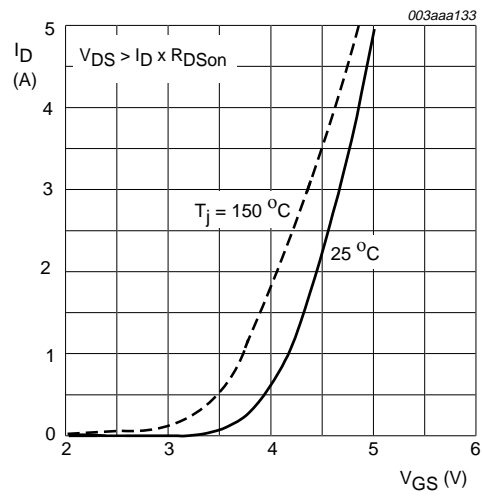
$T_j = 25\text{ }^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250\text{ }\mu\text{A}; V_{GS} = 0\text{ V}$	200	–	–	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 250\text{ }\mu\text{A}; V_{DS} = V_{GS}$; Figure 9	2	3	4	V
I_{DSS}	drain-source leakage current	$V_{DS} = 200\text{ V}; V_{GS} = 0\text{ V}$	–	–	25	μA
		$V_{DS} = 160\text{ V}; V_{GS} = 0\text{ V}; T_j = 125\text{ }^\circ\text{C}$	–	–	250	μA
I_{GSS}	gate-source leakage current	$V_{GS} = \pm 20\text{ V}; V_{DS} = 0\text{ V}$	–	10	100	nA
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 2.9\text{ A}$				
		$T_j = 25\text{ }^\circ\text{C}$; Figure 7 and 8	–	0.7	0.8	Ω
		$T_j = 150\text{ }^\circ\text{C}$; Figure 7 and 8	–	–	1.9	Ω
Dynamic characteristics						
g_{fs}	forward transconductance	$V_{DS} = 50\text{ V}; I_D = 2.9\text{ A}$	1.7	–	–	S
$Q_{g(tot)}$	total gate charge	$I_D = 4.8\text{ A}; V_{DD} = 160\text{ V}; V_{GS} = 10\text{ V}$; Figure 13	–	10	14	nC
Q_{gs}	gate-source charge		–	1.5	3.0	nC
Q_{gd}	gate-drain (Miller) charge		–	4.0	7.9	nC
C_{iss}	input capacitance	$V_{GS} = 0\text{ V}; V_{DD} = 25\text{ V}; f = 1\text{ MHz}$; Figure 11	–	280	–	pF
C_{oss}	output capacitance		–	41	–	pF
C_{riss}	reverse transfer capacitance		–	25	–	pF
$t_{d(on)}$	turn-on delay time	$V_{DD} = 100\text{ V}; R_D = 20\text{ }\Omega; V_{GS} = 10\text{ V};$ $R_G = 18\text{ }\Omega$	–	5.0	–	ns
t_r	rise time		–	17	–	ns
$t_{d(off)}$	turn-off delay time		–	22	–	ns
t_f	fall time		–	18	–	ns
Source-drain (reverse) diode						
V_{SD}	source-drain (diode forward) voltage	$I_S = 4.8\text{ A}; V_{GS} = 0\text{ V}$; Figure 12	–	–	1.8	V
t_{rr}	reverse recovery time	$I_S = 4.8\text{ A}; di_S/dt = -100\text{ A}/\mu\text{s};$ $V_{GS} = 0\text{ V}; V_{DS} = 30\text{ V}$	–	85	170	ns
Q_r	recovered charge		–	0.2	1.8	μC



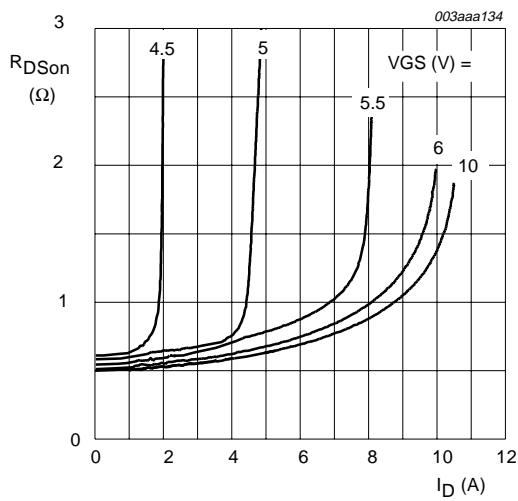
$T_j = 25\text{ }^\circ\text{C}$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



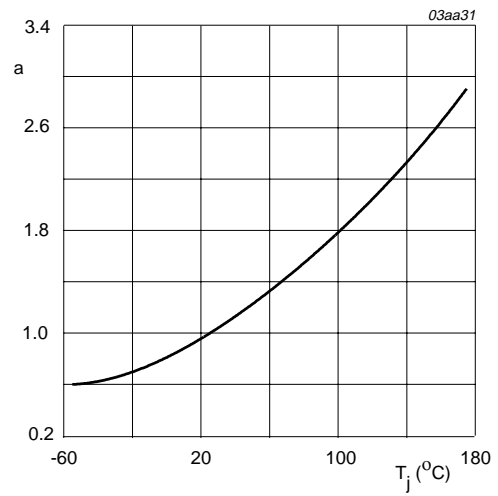
$T_j = 25\text{ }^\circ\text{C}$ and $150\text{ }^\circ\text{C}$; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.



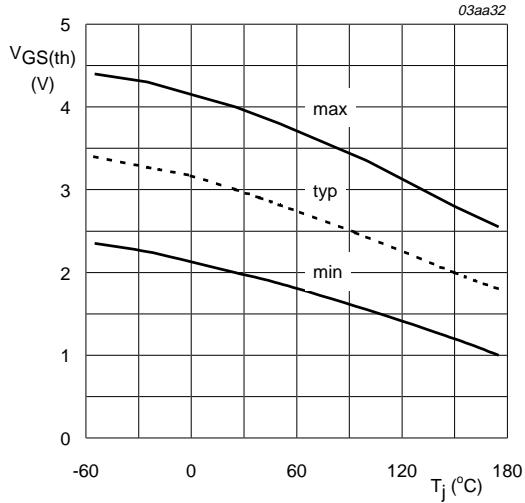
$T_j = 25\text{ }^\circ\text{C}$

Fig 7. Drain-source on-state resistance as a function of drain current; typical values.



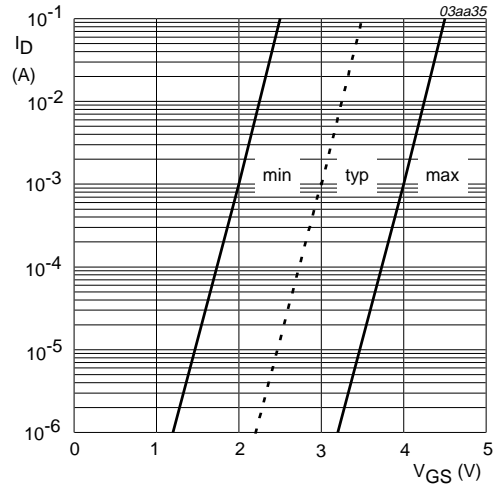
$$a = \frac{R_{DSon}}{R_{DSon(25^\circ\text{C})}}$$

Fig 8. Normalized drain source on-state resistance factor as a function of junction temperature.



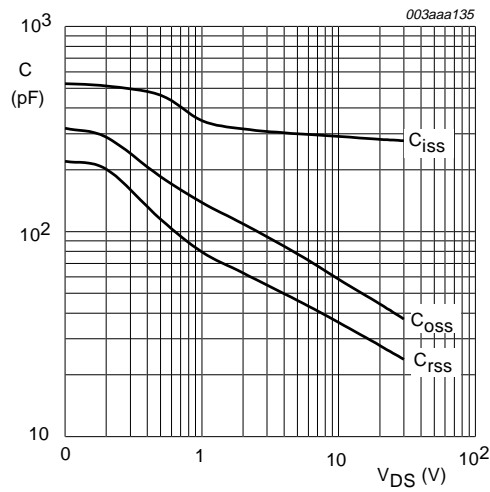
$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature.



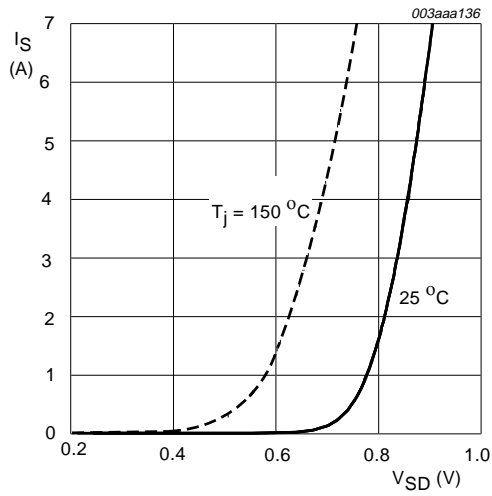
$T_j = 25 \text{ }^{\circ}C; V_{DS} = 5 \text{ V}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage.



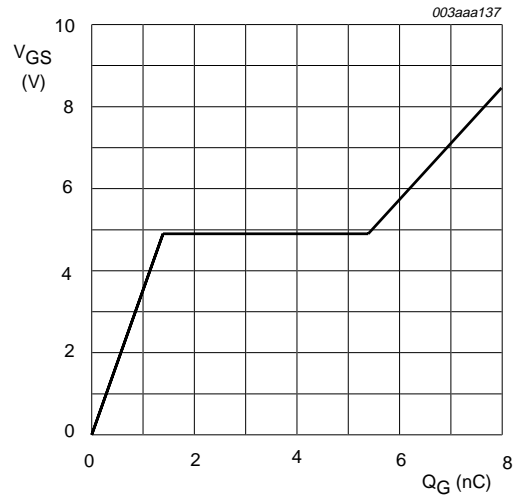
$V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.



$T_j = 25^\circ\text{C}$ and 150°C ; $V_{GS} = 0\text{ V}$

Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.



$I_D = 4.8\text{ A}$; $V_{DD} = 160\text{ V}$

Fig 13. Gate-source voltage as a function of gate charge; typical values.

9. Package outline

Plastic single-ended surface mounted package (Philips version of D-PAK); 3 leads (one lead cropped)

SOT428

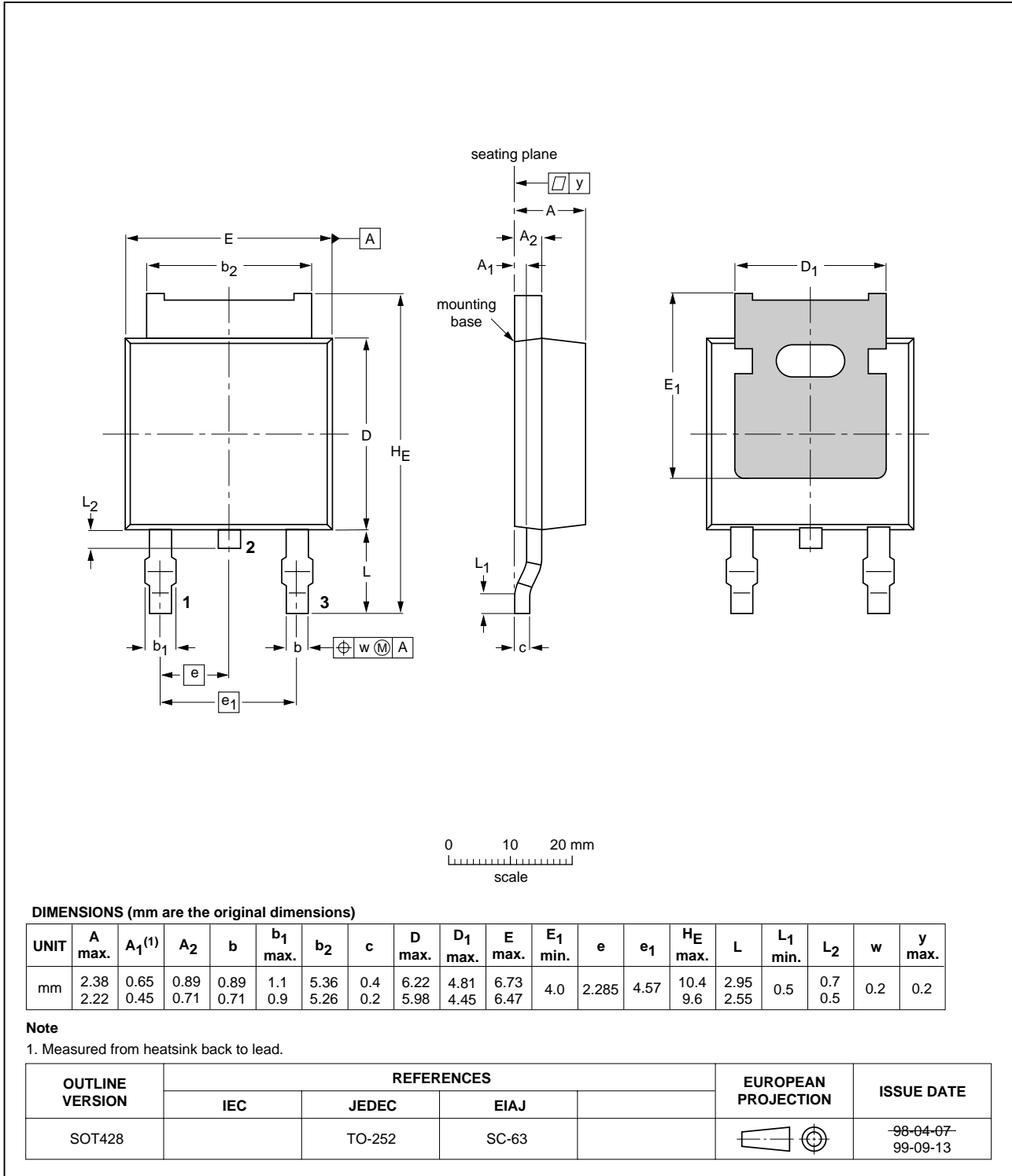


Fig 14. SOT428.

10. Revision history

Table 6: Revision history

Rev	Date	CPCN	Description
01	20010814	-	Product data; initial version

11. Data sheet status

Data sheet status ^[1]	Product status ^[2]	Definition
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL <http://www.semiconductors.philips.com>.

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